Interprence Searchi 10/771,998

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	763	(714/42).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L2	296	(714/54).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L3	1691	(714/718).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L4	973	(714/733).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L5	401	(714/734).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L6	804	(711/115).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L7	1257	(711/5).ccls.	US-PGPUB; USPAT	OR	ON	2007/03/15 17:29
L8	782	serial adj presence adj detect	US-PGPUB; USPAT	OR	ON	2007/03/15 17:30
L9	4742	(inject\$3 or insert\$3) same memory same (error or fault or bug\$3)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:30
L10	7488	(inject\$3 or insert\$3) same external same memory	US-PGPUB; USPAT	OR	ON	2007/03/15 17:30
L11	1124269	(column adj access adj strobe) or CAS	US-PGPUB; USPAT	OR	ON	2007/03/15 17:31
L12	9	9 same external same (data adj line)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:34
L13	0	12 and 8 and 11	US-PGPUB; USPAT	OR	ON	2007/03/15 17:34
L14	0	12 and 8 and 1	US-PGPUB; USPAT	OR	ON	2007/03/15 17:34
L15	0	12 and 8 and 2	US-PGPUB; USPAT	OR	ON	2007/03/15 17:34
L16	304	9 same external	US-PGPUB; USPAT	OR	ON	2007/03/15 17:34
L17	0	16 and 3 and 11 and (data adj line)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:35
L18	. 0	16 and 3 and 11 and (data adj line)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:35
L19	0	16 and 4 and (data adj line)	US-PGPUB; USPAT	OR	ON ·	2007/03/15 17:35
L20	1	16 and 5 and (data adj line)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:35
L21	0	16 and 6 and (data adj line)	US-PGPUB; USPAT	OR	ON	2007/03/15 17:35

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L22	0	16 and 7 and (data adj line)	US-PGPUB;	OR	ON	2007/03/15 17:36
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Hive: fault containment for shared-memory multiprocessors

J. Chapin, M. Rosenblum, S. Devine, T. Lahiri, D. Teodosiu, A. Gupta

December 1995 ACM SIGOPS Operating Systems Review , Proceedings of the fifteenth ACM symposium on Operating systems principles SOSP '95, Volume 29 Issue 5

Publisher: ACM Press

Full text available: pdf(1.90 MB)

Additional Information: full citation, references, citings, index terms

2 Software support for portable storage: Reliability mechanisms for file systems using



non-volatile memory as a metadata store Kevin M. Greenan, Ethan L. Miller

October 2006 Proceedings of the 6th ACM & IEEE International conference on **Embedded software EMSOFT '06**

Publisher: ACM Press

Full text available: R pdf(301.21 KB) Additional Information: full citation, abstract, references, index terms

Portable systems such as cell phones and portable media players commonly use nonvolatile RAM (NVRAM) to hold all of their data and metadata, and larger systems can store metadata in NVRAM to increase file system performance by reducing synchronization and transfer overhead between disk and memory data structures. Unfortunately, wayward writes from buggy software and random bit flips may result in an unreliable persistent store. We introduce two orthogonal and complementary approaches to reliabl ...

Keywords: error correcting codes, file system reliability, metadata, non-volatile memory, online consistency checking

Fast detection of communication patterns in distributed executions

Thomas Kunz, Michiel F. H. Seuren

November 1997 Proceedings of the 1997 conference of the Centre for Advanced Studies on Collaborative research CASCON '97

Publisher: IBM Press

Additional Information: full citation, abstract, references, index terms Full text available: pdf(4.21 MB)

Understanding distributed applications is a tedious and difficult task. Visualizations based on process-time diagrams are often used to obtain a better understanding of the



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Self-organizing systems: Ad hoc extensibility and access control

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Úlfar Erlingsson, John MacCormick

July 2006 ACM SIGOPS Operating Systems Review, Volume 40 Issue 3

Publisher: ACM Press

Full text available: pdf(200.54 KB) Additional Information: full citation, abstract, references, index terms

General-purpose, commercial software platforms are increasingly used as system building blocks, even for dependable systems. One reason for their generality, usefulness, and popular adoption is that these software platforms can evolve through ad hoc extensions: behavior tweaks outside the scope of supported platform interfaces. Unfortunately, such use of internal platform implementation details is fundamentally incompatible with security and reliability. Even so, platforms that exclude ad ...

82 Phoenix: Detecting and Recovering from Permanent Processor Design Bugs with Programmable Hardware

Smruti R. Sarangi, Abhishek Tiwari, Josep Torrellas

December 2006 Proceedings of the 39th Annual IEEE/ACM International Symposium on Microarchitecture MICRO '06

Publisher: IEEE Computer Society

Full text available: pdf(1.36 MB) Additional Information: full citation, abstract, index terms

Although processor design verification consumes ever-increasing resources, many design defects still slip into production silicon. In a few cases, such bugs have caused expensive chip recalls. To truly improve productivity, hardware bugs should be handled like system software ones, with vendors periodically releasing patches to fix hardware in the field. Based on an analysis of serious design defects in current AMD, Intel, IBM, and Motorola processors, this paper proposes and evaluates Phoenix - ...

83 An Accurate Analysis of the Effects of Soft Errors in the Instruction and Data Caches of a Pipelined Microprocessor

M. Rebaudengo, M. Sonza Reorda, M. Violante

March 2003 Proceedings of the conference on Design, Automation and Test in Europe - Volume 1 DATE '03

Publisher: IEEE Computer Society

Full text available: pdf(141.90 KB)

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Thu, 15 Mar 2007, 7:00:48 PM EST

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<u>#4</u>	((inject memory error <in>metadata) <and> (data line<in>metadata))<and> (serial presence detect<in>metadata)</in></and></in></and></in>	0
# <u>5</u>	((inject or insert <in>metadata) <and> (testing logic<in>metadata))<and> (serial presence detect<in>metadata)</in></and></in></and></in>	0
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